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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	CANbus, HDMI-CEC, I ² C, IrDA, LINbus, SPI, UART/USART, USB
Peripherals	DMA, I ² S, POR, PWM, WDT
Number of I/O	37
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.65V ~ 3.6V
Data Converters	A/D 10x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	48-LQFP
Supplier Device Package	48-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f072c8t6tr

Table 47.	Flash memory endurance and data retention	75
Table 48.	EMS characteristics	75
Table 49.	EMI characteristics	76
Table 50.	ESD absolute maximum ratings	77
Table 51.	Electrical sensitivities	77
Table 52.	I/O current injection susceptibility	78
Table 53.	I/O static characteristics	78
Table 54.	Output voltage characteristics	81
Table 55.	I/O AC characteristics	82
Table 56.	NRST pin characteristics	83
Table 57.	ADC characteristics	84
Table 58.	R_{AIN} max for $f_{ADC} = 14$ MHz	86
Table 59.	ADC accuracy	86
Table 60.	DAC characteristics	88
Table 61.	Comparator characteristics	90
Table 62.	TS characteristics	92
Table 63.	V_{BAT} monitoring characteristics	92
Table 64.	TIMx characteristics	92
Table 65.	IWDG min/max timeout period at 40 kHz (LSI)	93
Table 66.	WWDG min/max timeout value at 48 MHz (PCLK)	93
Table 67.	I ² C analog filter characteristics	94
Table 68.	SPI characteristics	94
Table 69.	I ² S characteristics	96
Table 70.	USB electrical characteristics	99
Table 71.	UFBGA100 package mechanical data	100
Table 72.	UFBGA100 recommended PCB design rules	101
Table 73.	LQPF100 package mechanical data	103
Table 74.	UFBGA64 package mechanical data	106
Table 75.	UFBGA64 recommended PCB design rules	107
Table 76.	LQFP64 package mechanical data	109
Table 77.	WLCSP49 package mechanical data	113
Table 78.	LQFP48 package mechanical data	116
Table 79.	UFQFPN48 package mechanical data	119
Table 80.	Package thermal characteristics	121
Table 81.	Ordering information scheme	124
Table 82.	Document revision history	125

Figure 4. LQFP100 package pinout

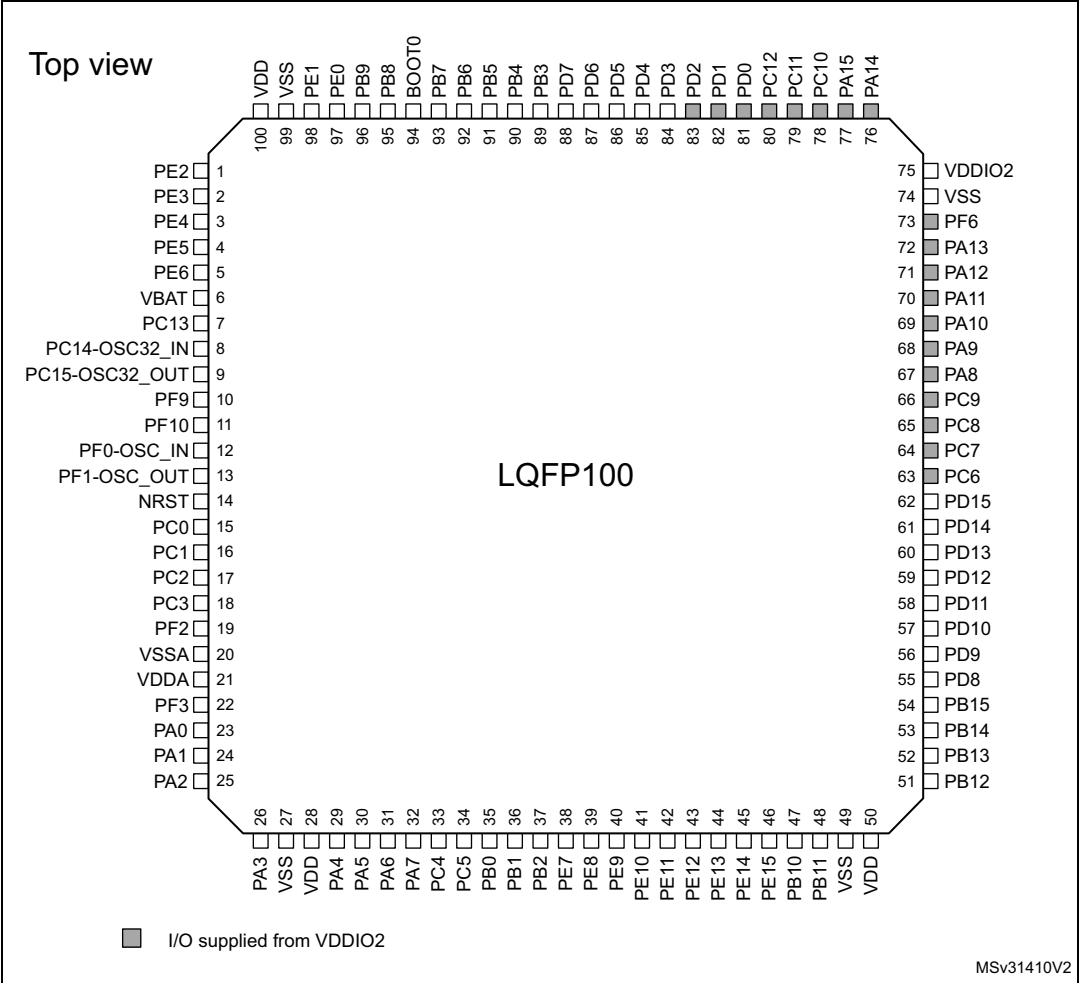


Table 13. STM32F072x8/xB pin definitions (continued)

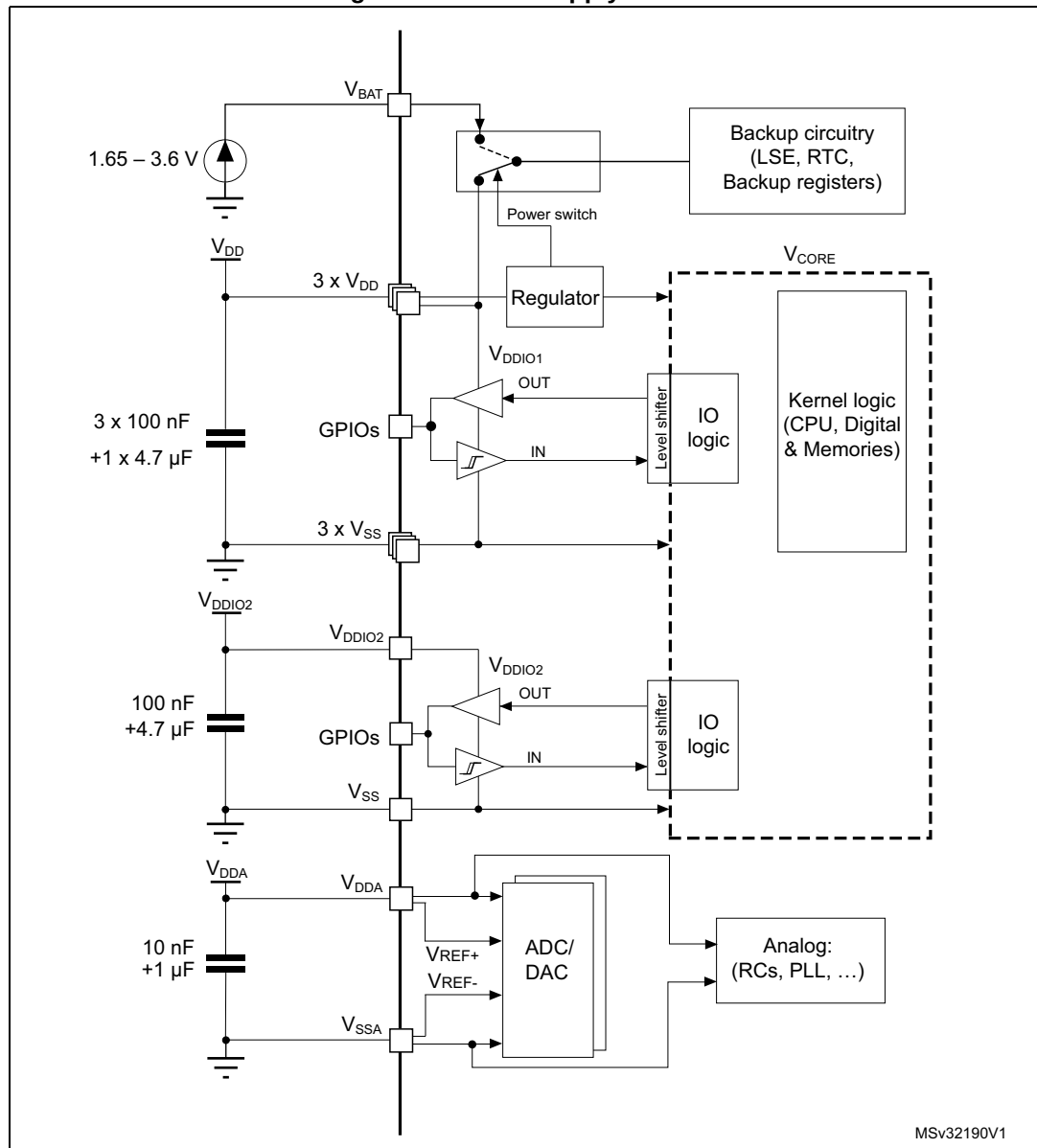
Pin numbers						Pin name (function upon reset)	Pin type	I/O structure	Notes	Pin functions	
UFBGA100	LQFP100	UFBGA64	LQFP64	LQFP48/UFQFPN48	WLCSP49					Alternate functions	Additional functions
K5	33	H5	24	-	-	PC4	I/O	TTa	-	EVENTOUT, USART3_TX	ADC_IN14
L5	34	H6	25	-	-	PC5	I/O	TTa	-	TSC_G3_IO1, USART3_RX	ADC_IN15, WKUP5
M5	35	F5	26	18	G5	PB0	I/O	TTa	-	TIM3_CH3, TIM1_CH2N, TSC_G3_IO2, EVENTOUT, USART3_CK	ADC_IN8
M6	36	G5	27	19	G4	PB1	I/O	TTa	-	TIM3_CH4, USART3_RTS, TIM14_CH1, TIM1_CH3N, TSC_G3_IO3	ADC_IN9
L6	37	G6	28	20	G3	PB2	I/O	FT	-	TSC_G3_IO4	-
M7	38	-	-	-	-	PE7	I/O	FT	-	TIM1_ETR	-
L7	39	-	-	-	-	PE8	I/O	FT	-	TIM1_CH1N	-
M8	40	-	-	-	-	PE9	I/O	FT	-	TIM1_CH1	-
L8	41	-	-	-	-	PE10	I/O	FT	-	TIM1_CH2N	-
M9	42	-	-	-	-	PE11	I/O	FT	-	TIM1_CH2	-
L9	43	-	-	-	-	PE12	I/O	FT	-	SPI1_NSS, I2S1_WS, TIM1_CH3N	-
M10	44	-	-	-	-	PE13	I/O	FT	-	SPI1_SCK, I2S1_CK, TIM1_CH3	-
M11	45	-	-	-	-	PE14	I/O	FT	-	SPI1_MISO, I2S1_MCK, TIM1_CH4	-
M12	46	-	-	-	-	PE15	I/O	FT	-	SPI1_MOSI, I2S1_SD, TIM1_BKIN	-
L10	47	G7	29	21	E3	PB10	I/O	FT	-	SPI2_SCK, I2C2_SCL, USART3_TX, CEC, TSC_SYNC, TIM2_CH3	-
L11	48	H7	30	22	G2	PB11	I/O	FT	-	USART3_RX, TIM2_CH4, EVENTOUT, TSC_G6_IO1, I2C2_SDA	-
F12	49	D5	31	23	D3	VSS	S	-	-	Ground	

Table 13. STM32F072x8/xB pin definitions (continued)

Pin numbers						Pin name (function upon reset)	Pin type	I/O structure	Notes	Pin functions	
UFBGA100	LQFP100	UFBGA64	LQFP64	LQFP48/JUFQFPN48	WLCSP49					Alternate functions	Additional functions
C10	79	B6	52	-	-	PC11	I/O	FT	(3)	USART3_RX, USART4_RX	-
B10	80	C5	53	-	-	PC12	I/O	FT	(3)	USART3_CK, USART4_CK	-
C9	81	-	-	-	-	PD0	I/O	FT	(3)	SPI2_NSS, I2S2_WS, CAN_RX	-
B9	82	-	-	-	-	PD1	I/O	FT	(3)	SPI2_SCK, I2S2_CK, CAN_TX	-
C8	83	B5	54	-	-	PD2	I/O	FT	(3)	USART3_RTS, TIM3_ETR	-
B8	84	-	-	-	-	PD3	I/O	FT	-	SPI2_MISO, I2S2_MCK, USART2_CTS	-
B7	85	-	-	-	-	PD4	I/O	FT	-	SPI2_MOSI, I2S2_SD, USART2_RTS	-
A6	86	-	-	-	-	PD5	I/O	FT	-	USART2_TX	-
B6	87	-	-	-	-	PD6	I/O	FT	-	USART2_RX	-
A5	88	-	-	-	-	PD7	I/O	FT	-	USART2_CK	-
A8	89	A5	55	39	A3	PB3	I/O	FT	-	SPI1_SCK, I2S1_CK, TIM2_CH2, TSC_G5_IO1, EVENTOUT	-
A7	90	A4	56	40	A4	PB4	I/O	FT	-	SPI1_MISO, I2S1_MCK, TIM17_BKIN, TIM3_CH1, TSC_G5_IO2, EVENTOUT	-
C5	91	C4	57	41	B4	PB5	I/O	FT	-	SPI1_MOSI, I2S1_SD, I2C1_SMBA, TIM16_BKIN, TIM3_CH2	WKUP6
B5	92	D3	58	42	C4	PB6	I/O	FTf	-	I2C1_SCL, USART1_TX, TIM16_CH1N, TSC_G5_IO3	-

6.1.6 Power supply scheme

Figure 13. Power supply scheme



Caution: Each power supply pair (V_{DD}/V_{SS} , V_{DDA}/V_{SSA} etc.) must be decoupled with filtering ceramic capacitors as shown above. These capacitors must be placed as close as possible to, or below, the appropriate pins on the underside of the PCB to ensure the good functionality of the device.

Table 33. Typical current consumption, code executing from Flash memory, running from HSE 8 MHz crystal

Symbol	Parameter	f _{HCLK}	Typical consumption in Run mode		Typical consumption in Sleep mode		Unit
			Peripherals enabled	Peripherals disabled	Peripherals enabled	Peripherals disabled	
I _{DD}	Current consumption from V _{DD} supply	48 MHz	24.1	13.5	14.6	3.5	mA
		36 MHz	18.3	10.5	11.1	2.9	
		32 MHz	16.5	9.6	10.0	2.7	
		24 MHz	12.9	7.6	7.8	2.2	
		16 MHz	8.9	5.3	5.5	1.7	
		8 MHz	4.8	3.1	3.1	1.2	
		4 MHz	3.1	2.1	2.2	1.1	
		2 MHz	2.1	1.6	1.6	1.0	
		1 MHz	1.6	1.3	1.4	1.0	
		500 kHz	1.3	1.2	1.2	1.0	
I _{DDA}	Current consumption from V _{DDA} supply	48 MHz	163.3				μA
		36 MHz	124.3				
		32 MHz	111.9				
		24 MHz	87.1				
		16 MHz	62.5				
		8 MHz	2.5				
		4 MHz	2.5				
		2 MHz	2.5				
		1 MHz	2.5				
		500 kHz	2.5				

I/O system current consumption

The current consumption of the I/O system has two components: static and dynamic.

I/O static current consumption

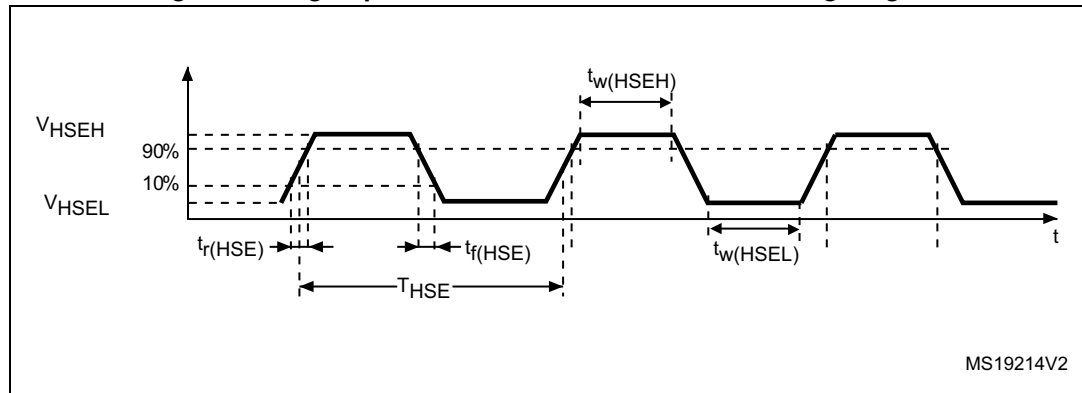
All the I/Os used as inputs with pull-up generate current consumption when the pin is externally held low. The value of this current consumption can be simply computed by using the pull-up/pull-down resistors values given in [Table 53: I/O static characteristics](#).

For the output pins, any external pull-down or external load must also be considered to estimate the current consumption.

Additional I/O current consumption is due to I/Os configured as inputs if an intermediate voltage level is externally applied. This current consumption is caused by the input Schmitt

1. Guaranteed by design, not tested in production.

Figure 15. High-speed external clock source AC timing diagram



Low-speed external user clock generated from an external source

In bypass mode the LSE oscillator is switched off and the input pin is a standard GPIO.

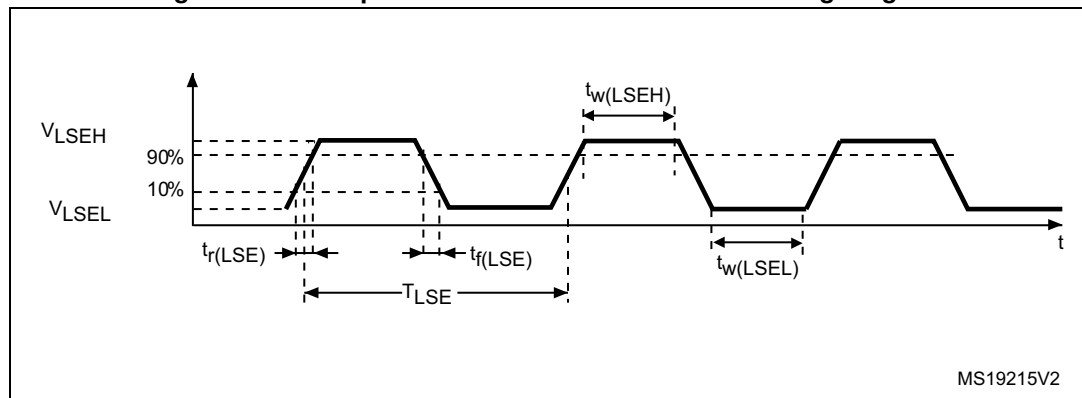
The external clock signal has to respect the I/O characteristics in [Section 6.3.14](#). However, the recommended clock input waveform is shown in [Figure 16](#).

Table 38. Low-speed external user clock characteristics

Symbol	Parameter ⁽¹⁾	Min	Typ	Max	Unit
f_{LSE_ext}	User external clock source frequency	-	32.768	1000	kHz
V_{LSEH}	OSC32_IN input pin high level voltage	$0.7 V_{DDIOx}$	-	V_{DDIOx}	V
V_{LSEL}	OSC32_IN input pin low level voltage	V_{SS}	-	$0.3 V_{DDIOx}$	
$t_{w(LSEH)}$ $t_{w(LSEL)}$	OSC32_IN high or low time	450	-	-	ns
$t_{r(LSE)}$ $t_{f(LSE)}$	OSC32_IN rise or fall time	-	-	50	

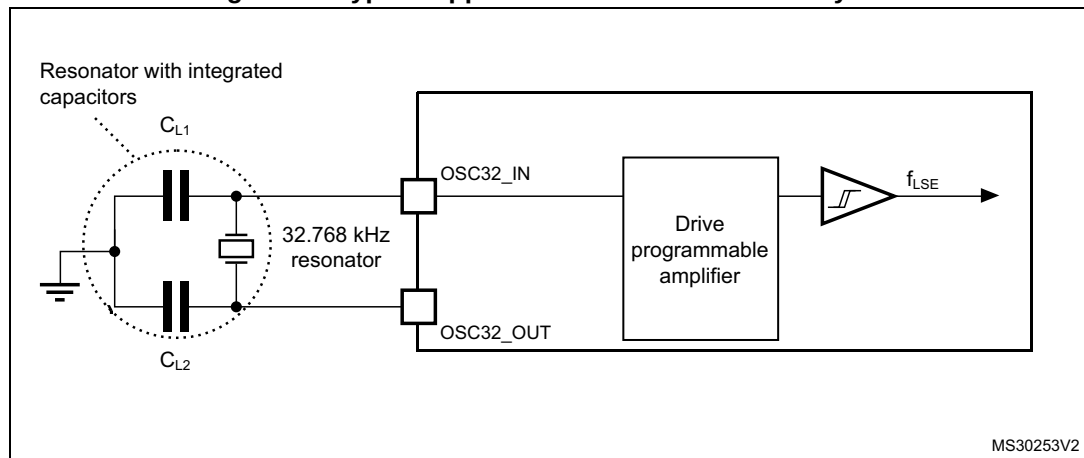
1. Guaranteed by design, not tested in production.

Figure 16. Low-speed external clock source AC timing diagram



Note: For information on selecting the crystal, refer to the application note AN2867 "Oscillator design guide for ST microcontrollers" available from the ST website www.st.com.

Figure 18. Typical application with a 32.768 kHz crystal



Note: An external resistor is not required between OSC32_IN and OSC32_OUT and it is forbidden to add one.

6.3.8 Internal clock source characteristics

The parameters given in [Table 41](#) are derived from tests performed under ambient temperature and supply voltage conditions summarized in [Table 24: General operating conditions](#). The provided curves are characterization results, not tested in production.

High-speed internal 48 MHz (HSI48) RC oscillator

Table 43. HSI48 oscillator characteristics⁽¹⁾

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{HSI48}	Frequency	-	-	48	-	MHz
TRIM	HSI48 user-trimming step	-	0.09 ⁽²⁾	0.14	0.2 ⁽²⁾	%
DuCy _(HSI48)	Duty cycle	-	45 ⁽²⁾	-	55 ⁽²⁾	%
$\text{ACC}_{\text{HSI48}}$	Accuracy of the HSI48 oscillator (factory calibrated)	$T_A = -40 \text{ to } 105 \text{ }^\circ\text{C}$	-4.9 ⁽³⁾	-	4.7 ⁽³⁾	%
		$T_A = -10 \text{ to } 85 \text{ }^\circ\text{C}$	-4.1 ⁽³⁾	-	3.7 ⁽³⁾	%
		$T_A = 0 \text{ to } 70 \text{ }^\circ\text{C}$	-3.8 ⁽³⁾	-	3.4 ⁽³⁾	%
		$T_A = 25 \text{ }^\circ\text{C}$	-2.8	-	2.9	%
$t_{\text{su(HSI48)}}$	HSI48 oscillator startup time	-	-	-	6 ⁽²⁾	μs
$I_{\text{DDA(HSI48)}}$	HSI48 oscillator power consumption	-	-	312	350 ⁽²⁾	μA

1. $V_{\text{DDA}} = 3.3 \text{ V}$, $T_A = -40 \text{ to } 105 \text{ }^\circ\text{C}$ unless otherwise specified.
2. Guaranteed by design, not tested in production.
3. Data based on characterization results, not tested in production.

Figure 21. HSI48 oscillator accuracy characterization results

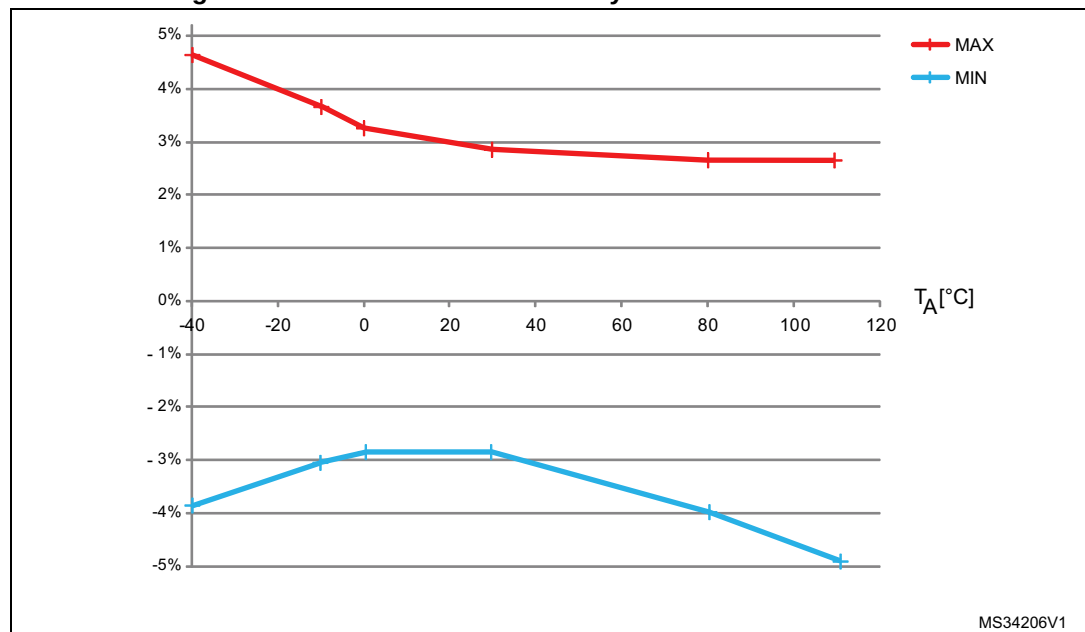


Table 57. ADC characteristics (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$f_{\text{TRIG}}^{(2)}$	External trigger frequency	$f_{\text{ADC}} = 14 \text{ MHz}$, 12-bit resolution	-	-	823	kHz
		12-bit resolution	-	-	17	$1/f_{\text{ADC}}$
V_{AIN}	Conversion voltage range	-	0	-	V_{DDA}	V
$R_{\text{AIN}}^{(2)}$	External input impedance	See Equation 1 and Table 58 for details	-	-	50	k Ω
$R_{\text{ADC}}^{(2)}$	Sampling switch resistance	-	-	-	1	k Ω
$C_{\text{ADC}}^{(2)}$	Internal sample and hold capacitor	-	-	-	8	pF
$t_{\text{CAL}}^{(2)(3)}$	Calibration time	$f_{\text{ADC}} = 14 \text{ MHz}$	5.9			μs
		-	83			$1/f_{\text{ADC}}$
$W_{\text{LATENCY}}^{(2)(4)}$	ADC_DR register ready latency	ADC clock = HSI14	1.5 ADC cycles + 2 f_{PCLK} cycles	-	1.5 ADC cycles + 3 f_{PCLK} cycles	-
		ADC clock = PCLK/2	-	4.5	-	f_{PCLK} cycle
		ADC clock = PCLK/4	-	8.5	-	f_{PCLK} cycle
$t_{\text{latr}}^{(2)}$	Trigger conversion latency	$f_{\text{ADC}} = f_{\text{PCLK}}/2 = 14 \text{ MHz}$	0.196			μs
		$f_{\text{ADC}} = f_{\text{PCLK}}/2$	5.5			$1/f_{\text{PCLK}}$
		$f_{\text{ADC}} = f_{\text{PCLK}}/4 = 12 \text{ MHz}$	0.219			μs
		$f_{\text{ADC}} = f_{\text{PCLK}}/4$	10.5			$1/f_{\text{PCLK}}$
		$f_{\text{ADC}} = f_{\text{HSI14}} = 14 \text{ MHz}$	0.179	-	0.250	μs
Jitter _{ADC}	ADC jitter on trigger conversion	$f_{\text{ADC}} = f_{\text{HSI14}}$	-	1	-	$1/f_{\text{HSI14}}$
$t_{\text{S}}^{(2)}$	Sampling time	$f_{\text{ADC}} = 14 \text{ MHz}$	0.107	-	17.1	μs
		-	1.5	-	239.5	$1/f_{\text{ADC}}$
$t_{\text{STAB}}^{(2)}$	Stabilization time	-	14			$1/f_{\text{ADC}}$
$t_{\text{CONV}}^{(2)}$	Total conversion time (including sampling time)	$f_{\text{ADC}} = 14 \text{ MHz}$, 12-bit resolution	1	-	18	μs
		12-bit resolution	14 to 252 (t_{S} for sampling + 12.5 for successive approximation)			$1/f_{\text{ADC}}$

1. During conversion of the sampled value (12.5 x ADC clock period), an additional consumption of 100 μA on I_{DDA} and 60 μA on I_{DD} should be taken into account.
2. Guaranteed by design, not tested in production.
3. Specified value includes only ADC timing. It does not include the latency of the register access.
4. This parameter specify latency for transfer of the conversion result to the ADC_DR register. EOC flag is set at this time.

Equation 1: R_{AIN} max formula

$$R_{AIN} < \frac{T_s}{f_{ADC} \times C_{ADC} \times \ln(2^{N+2})} - R_{ADC}$$

The formula above ([Equation 1](#)) is used to determine the maximum external impedance allowed for an error below 1/4 of LSB. Here N = 12 (from 12-bit resolution).

Table 58. R_{AIN} max for $f_{ADC} = 14$ MHz

T_s (cycles)	t_s (μs)	R_{AIN} max (kΩ) ⁽¹⁾
1.5	0.11	0.4
7.5	0.54	5.9
13.5	0.96	11.4
28.5	2.04	25.2
41.5	2.96	37.2
55.5	3.96	50
71.5	5.11	NA
239.5	17.1	NA

1. Guaranteed by design, not tested in production.

Table 59. ADC accuracy⁽¹⁾⁽²⁾⁽³⁾

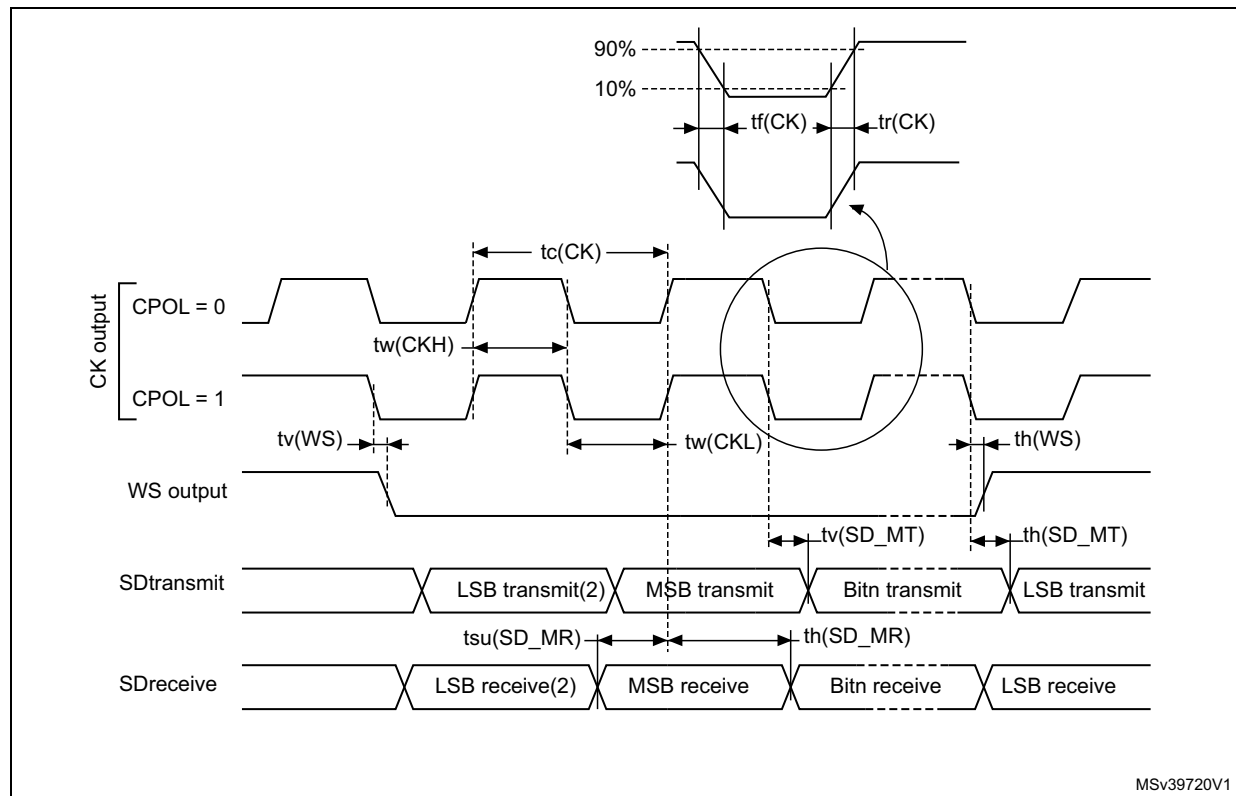
Symbol	Parameter	Test conditions	Typ	Max ⁽⁴⁾	Unit
ET	Total unadjusted error	$f_{PCLK} = 48$ MHz, $f_{ADC} = 14$ MHz, $R_{AIN} < 10$ kΩ $V_{DDA} = 3$ V to 3.6 V $T_A = 25$ °C	±1.3	±2	LSB
EO	Offset error		±1	±1.5	
EG	Gain error		±0.5	±1.5	
ED	Differential linearity error		±0.7	±1	
EL	Integral linearity error		±0.8	±1.5	
ET	Total unadjusted error	$f_{PCLK} = 48$ MHz, $f_{ADC} = 14$ MHz, $R_{AIN} < 10$ kΩ $V_{DDA} = 2.7$ V to 3.6 V $T_A = -40$ to 105 °C	±3.3	±4	LSB
EO	Offset error		±1.9	±2.8	
EG	Gain error		±2.8	±3	
ED	Differential linearity error		±0.7	±1.3	
EL	Integral linearity error		±1.2	±1.7	
ET	Total unadjusted error	$f_{PCLK} = 48$ MHz, $f_{ADC} = 14$ MHz, $R_{AIN} < 10$ kΩ $V_{DDA} = 2.4$ V to 3.6 V $T_A = 25$ °C	±3.3	±4	LSB
EO	Offset error		±1.9	±2.8	
EG	Gain error		±2.8	±3	
ED	Differential linearity error		±0.7	±1.3	
EL	Integral linearity error		±1.2	±1.7	

1. ADC DC accuracy values are measured after internal calibration.

6.3.17 DAC electrical specifications

Table 60. DAC characteristics

Symbol	Parameter	Min	Typ	Max	Unit	Comments
V_{DDA}	Analog supply voltage for DAC ON	2.4	-	3.6	V	-
$R_{LOAD}^{(1)}$	Resistive load with buffer ON	5	-	-	k Ω	Load connected to V_{SSA}
		25	-	-	k Ω	Load connected to V_{DDA}
$R_O^{(1)}$	Impedance output with buffer OFF	-	-	15	k Ω	When the buffer is OFF, the Minimum resistive load between DAC_OUT and V_{SS} to have a 1% accuracy is 1.5 M Ω
$C_{LOAD}^{(1)}$	Capacitive load	-	-	50	pF	Maximum capacitive load at DAC_OUT pin (when the buffer is ON).
DAC_OUT_min ⁽¹⁾	Lower DAC_OUT voltage with buffer ON	0.2	-	-	V	It gives the maximum output excursion of the DAC. It corresponds to 12-bit input code (0x0E0) to (0xF1C) at $V_{DDA} = 3.6$ V and (0x155) and (0xEAB) at $V_{DDA} = 2.4$ V
DAC_OUT_max ⁽¹⁾	Higher DAC_OUT voltage with buffer ON	-	-	$V_{DDA} - 0.2$	V	
DAC_OUT_min ⁽¹⁾	Lower DAC_OUT voltage with buffer OFF	-	0.5	-	mV	It gives the maximum output excursion of the DAC.
DAC_OUT_max ⁽¹⁾	Higher DAC_OUT voltage with buffer OFF	-	-	$V_{DDA} - 1\text{LSB}$	V	
$I_{DDA}^{(1)}$	DAC DC current consumption in quiescent mode ⁽²⁾	-	-	600	μ A	With no load, middle code (0x800) on the input
		-	-	700	μ A	With no load, worst code (0xF1C) on the input
DNL ⁽³⁾	Differential non linearity Difference between two consecutive code-1LSB)	-	-	± 0.5	LSB	Given for the DAC in 10-bit configuration
		-	-	± 2	LSB	Given for the DAC in 12-bit configuration
INL ⁽³⁾	Integral non linearity (difference between measured value at Code i and the value at Code i on a line drawn between Code 0 and last Code 1023)	-	-	± 1	LSB	Given for the DAC in 10-bit configuration
		-	-	± 4	LSB	Given for the DAC in 12-bit configuration
Offset ⁽³⁾	Offset error (difference between measured value at Code (0x800) and the ideal value = $V_{DDA}/2$)	-	-	± 10	mV	-
		-	-	± 3	LSB	Given for the DAC in 10-bit at $V_{DDA} = 3.6$ V
		-	-	± 12	LSB	Given for the DAC in 12-bit at $V_{DDA} = 3.6$ V

Figure 34. I²S master timing diagram (Philips protocol)

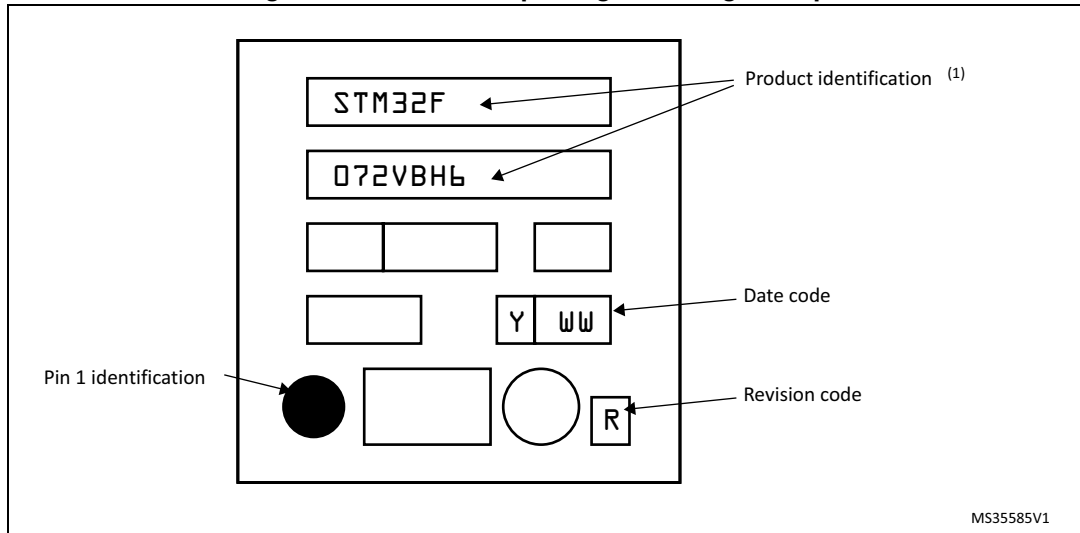
1. Data based on characterization results, not tested in production.
2. LSB transmit/receive of the previously transmitted byte. No LSB transmit/receive is sent before the first byte.

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Other optional marking or inset/upset marks, which identify the parts throughout supply chain operations, are not indicated below.

Figure 37. UFBGA100 package marking example



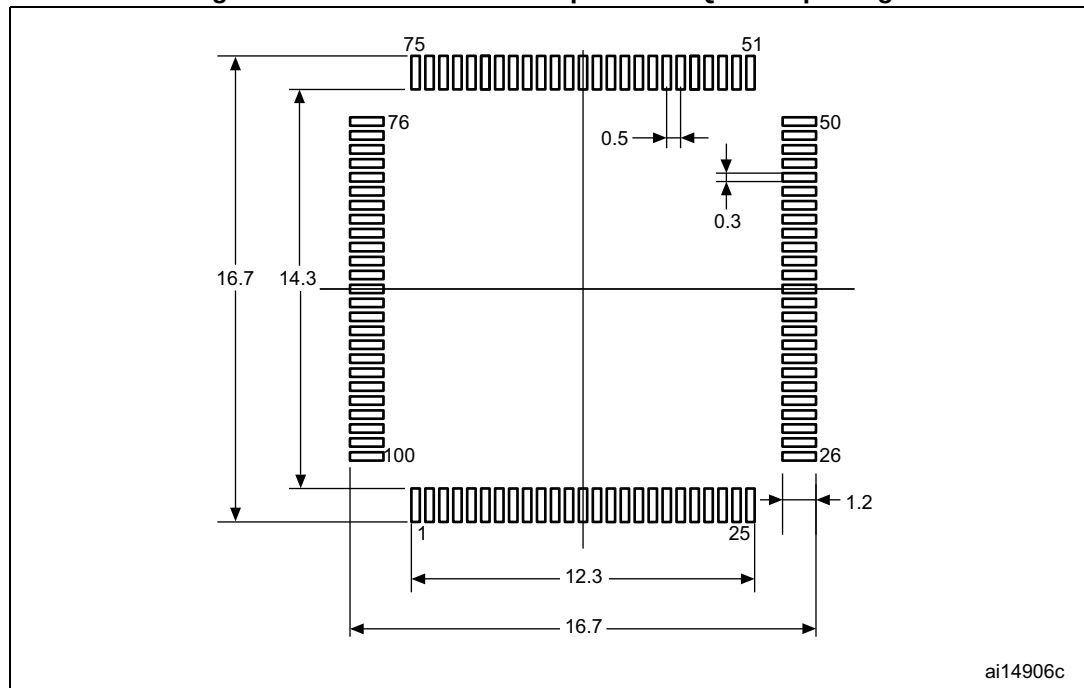
1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.

Table 73. LQPF100 package mechanical data (continued)

Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
E1	13.800	14.000	14.200	0.5433	0.5512	0.5591
E3	-	12.000	-	-	0.4724	-
e	-	0.500	-	-	0.0197	-
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
k	0.0°	3.5°	7.0°	0.0°	3.5°	7.0°
ccc	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 39. Recommended footprint for LQFP100 package



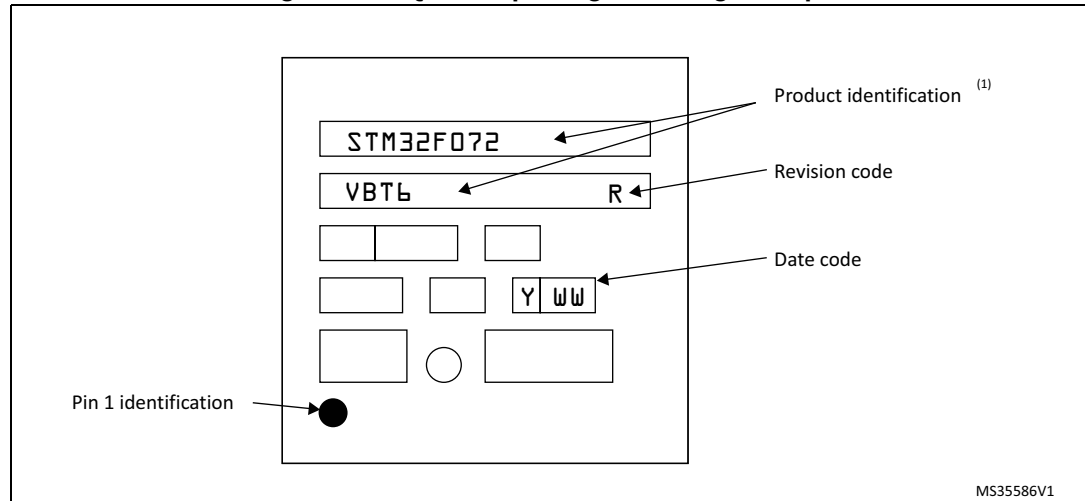
1. Dimensions are expressed in millimeters.

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Other optional marking or inset/upset marks, which identify the parts throughout supply chain operations, are not indicated below.

Figure 40. LQFP100 package marking example



1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.

Table 74. UFBGA64 package mechanical data (continued)

Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
A	0.460	0.530	0.600	0.0181	0.0209	0.0236
ddd	-	-	0.080	-	-	0.0031
eee	-	-	0.150	-	-	0.0059
fff	-	-	0.050	-	-	0.0020

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 42. Recommended footprint for UFBGA64 package

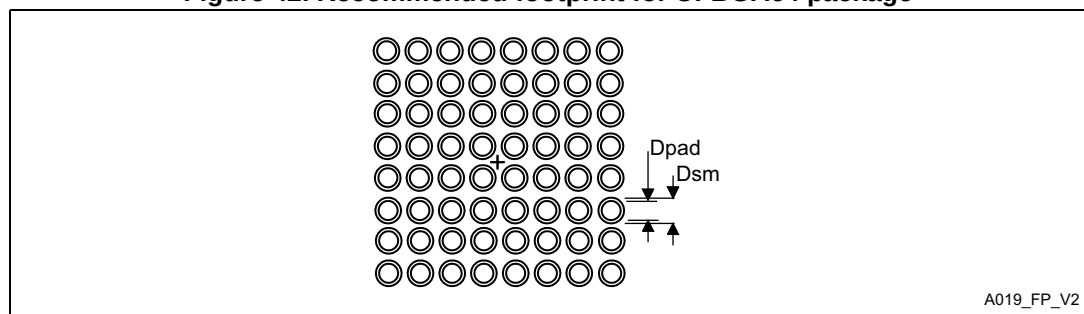


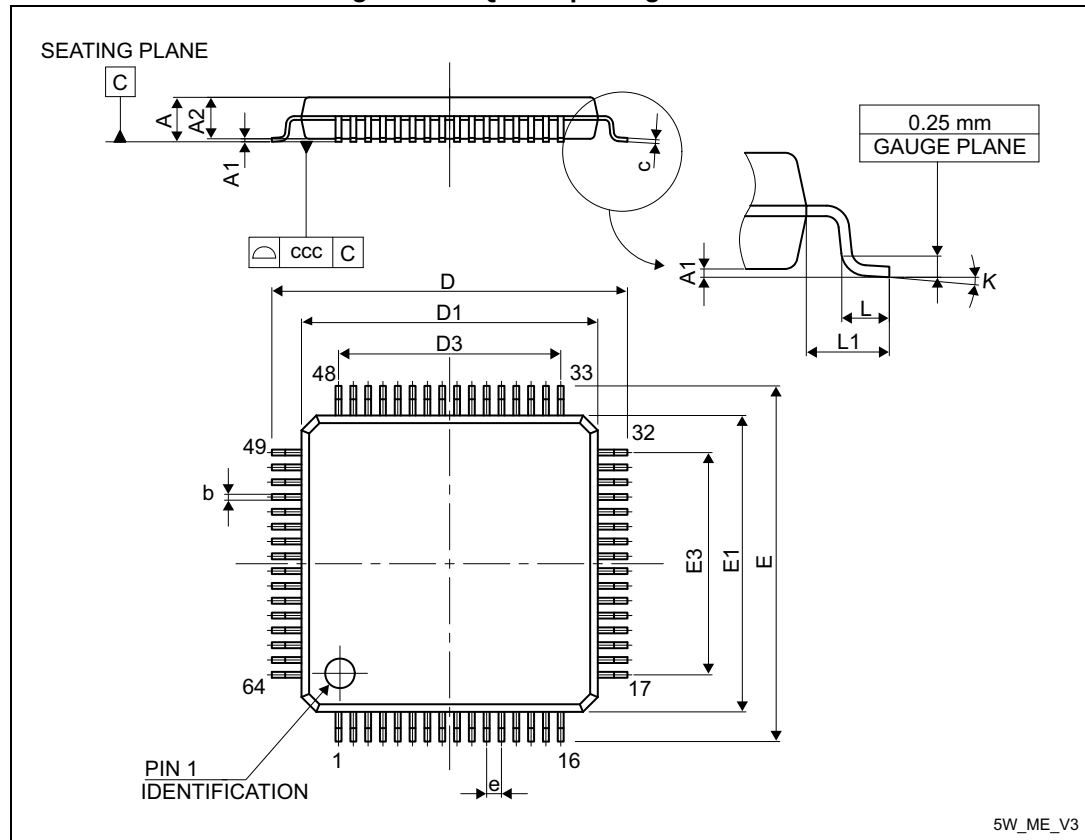
Table 75. UFBGA64 recommended PCB design rules

Dimension	Recommended values
Pitch	0.5
Dpad	0.280 mm
Dsm	0.370 mm typ. (depends on the soldermask registration tolerance)
Stencil opening	0.280 mm
Stencil thickness	Between 0.100 mm and 0.125 mm
Pad trace width	0.100 mm

7.4 LQFP64 package information

LQFP64 is a 64-pin, 10 x 10 mm low-profile quad flat package.

Figure 44. LQFP64 package outline



5W_ME_V3

1. Drawing is not to scale.

Table 76. LQFP64 package mechanical data

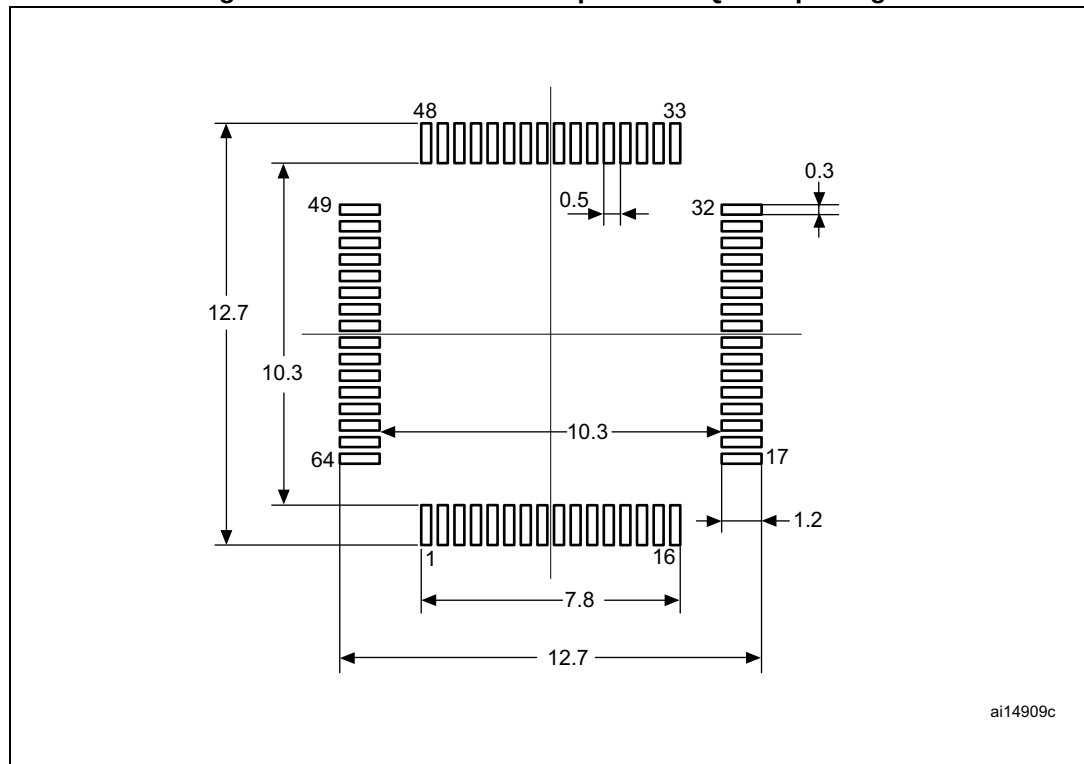
Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	-	12.000	-	-	0.4724	-
D1	-	10.000	-	-	0.3937	-
D3	-	7.500	-	-	0.2953	-
E	-	12.000	-	-	0.4724	-
E1	-	10.000	-	-	0.3937	-

Table 76. LQFP64 package mechanical data (continued)

Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
E3	-	7.500	-	-	0.2953	-
e	-	0.500	-	-	0.0197	-
K	0°	3.5°	7°	0°	3.5°	7°
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
ccc	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 45. Recommended footprint for LQFP64 package



1. Dimensions are expressed in millimeters.

Using the values obtained in [Table 80](#) T_{Jmax} is calculated as follows:

– For LQFP64, 45 °C/W

$$T_{Jmax} = 100\text{ °C} + (45\text{ °C/W} \times 134\text{ mW}) = 100\text{ °C} + 6.03\text{ °C} = 106.03\text{ °C}$$

This is above the range of the suffix 6 version parts ($-40 < T_J < 105\text{ °C}$).

In this case, parts must be ordered at least with the temperature range suffix 7 (see [Section 8: Ordering information](#)) unless we reduce the power dissipation in order to be able to use suffix 6 parts.

Refer to [Figure 55](#) to select the required temperature range (suffix 6 or 7) according to your temperature or power requirements.

Figure 55. LQFP64 P_D max versus T_A

